Hybrid 5p153 Traveler

May 3, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 5P153 has die: 158-041 158-042 158-044 158-045 158-046

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 5p153 classification info. Created 12:20:08 05/03/00

Hybrid 5p153 quality: fair
Chip classification: good fair fair good fair
Bad channels (chip-channel): 2-95
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-10-112 1-10-113 1-11-112
   1-23-112 1-43-112 1-45-112 2-0-94 2-11-94 2-13-94 2-14-94 2-15-94
   2-2-94 2-38-94 2-4-94 2-42-94 2-43-94 4-5-74
Channels at pedestal needed for DCMS: 29.6 28.6 29.7 30.7 30.6
```

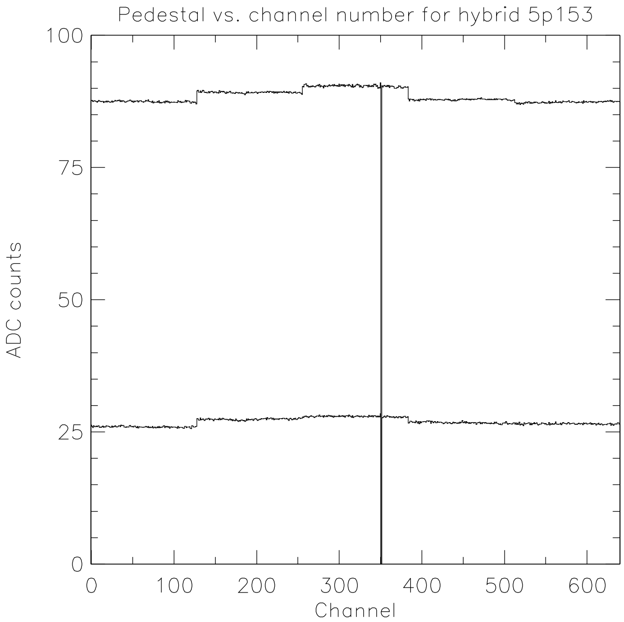
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

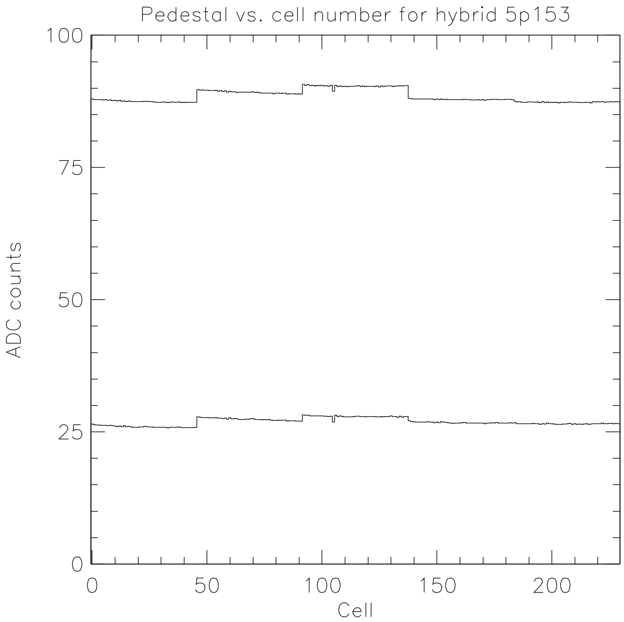
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

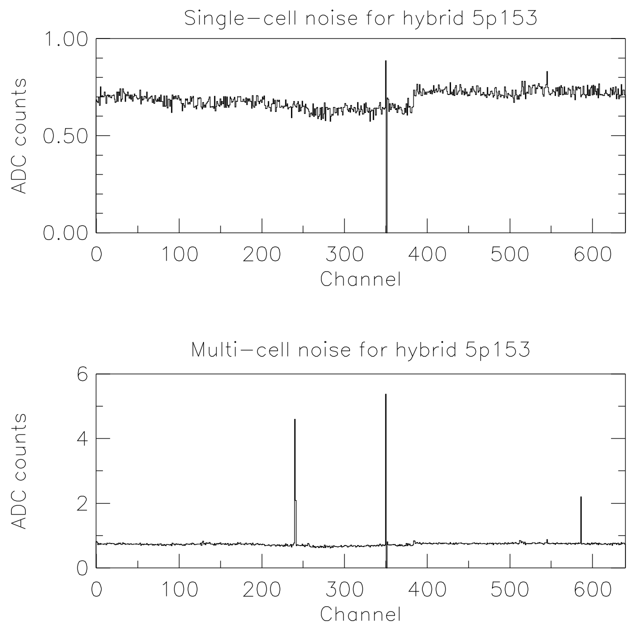
Pedestal vs. Pipeline Cell ID



6 Noise

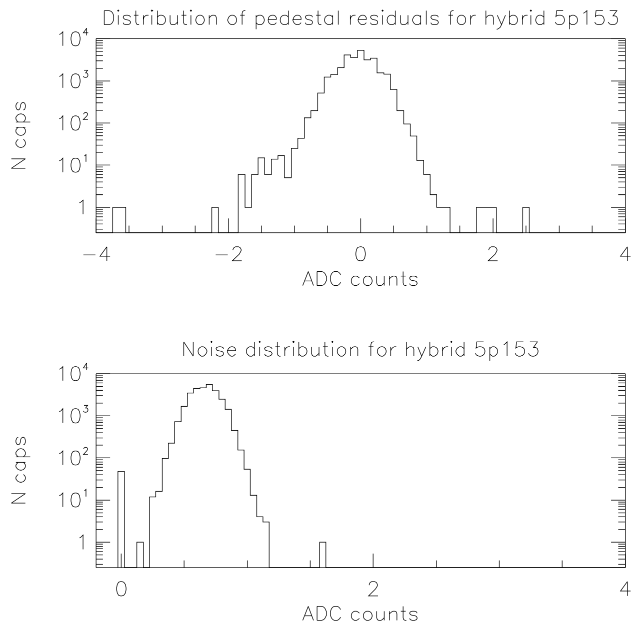
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in